

Corn Yields Continue To Increase



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This past week, Dr. Bill Wiebold, University of Missouri Extension State Crop Specialist, showed corn yield data over decades of corn research how corn yields have increased. The data showed that the genetics that increased yield were from increased population and ability to handle stress.

The data he showed was very interesting in that corn breeders over time have spent time managing crop stresses and continuing to add traits that allow more plants per acre.

Those who are promoting biotechnology have given growers the impression that we will reach

very high corn yields in the future. We may very well. But the data from this research indicates yield increases will be from genetic packages such as drought tolerance.

One part of his data showed corn planted at a very low plant population. This planting contained different hybrids from each decade and then measured for yield. The yields at this low population stayed the same and did not increase across decades of time. If we had been changing the genetics of yield, the data would have showed a yield increase over time with better genetics.

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